

Features

- 2.15×2.40mm with 1.80mm lens
- High Brightness
- Water Clear
- Small double-end package
- EIA Std. package
- Mono-color type
- Special packaging available upon request
- High reliability

Applications

- PCB mounted infrared sensor
- · Infrared emitting for miniature light barrier
- Floppy disk drive
- Optoelectronic switch
- Smoke detector

Description

The INA-912AHIR25 is high brightness SMD Axial LED. It is a 1.8mm Lens type LED which can be used in various applications.

Recommended Solder Pattern

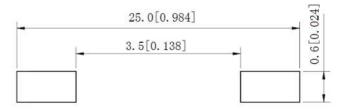


Figure 1. INA-912AHIR25 Solder Pattern

Package Dimensions in mm

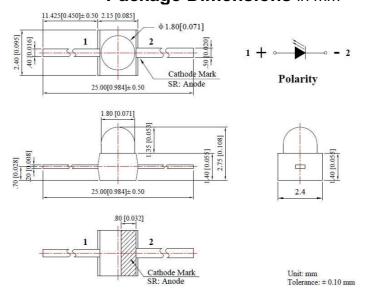


Figure 2. INA-912AHIR25 Package Dimensions

Notes

- 1. All dimensions are in millimeters (inches).
- 2. Tolerance is ± 0.25 mm (.010") unless otherwise noted.



Absolute Maximum Rating at 25°C (Note)

Product	Emission Color	P _d (mW)	I _F (mA)	I _{FP} * (A)	V _R (V)	T _{OP} (°C)	Тsт (°С)
INA-912AHIR25	Infrared	90	50	1.00	5	-40°C~+80°C	-40°C~+85°C

Notes

- 1. Derate linearly as shown in derating curve.
- 2. Duty Factor = 10%, Frequency = 1 kHz

Electrical Characteristics T_A = 25°C (Note)

	Product Emission Color		V _F (V)				λ(nm)		Viewing Angle	Ee (r		mW/sr)						
Product		I _F (mA)	IF=10 IF=20mA tp=10 tp/T=		=100)μs,	λ _D	λ _P	Δλ	201/2	IF	=201	mA	tp=	:100n =100µ T=0.	us,		
INA-912AHIR25	Infrared	20	min	typ	max	min	typ	max		940	50	25	min	typ	max	min	typ	max
IIVA-91ZAFIRZS	iiiiaieu	20	8.0	1.2	1.5	-	1.6	1.8	-	340	30	25	3	6	1	-	15	-

Notes

- 1. Performance guaranteed only under conditions listed in above tables.
- 2. A luminous intensity is measured with a light sensor and filter combination that approximates the CIE eye-response curve.
- 3. 201/2 is the o -axis angle where the luminous intensity is 1/2 the peak intensity.
- 4. The dominant wavelength (λd) is derived from the CIÉ chromaticity diagram and represents the single wavelength which defines the color of the device.

ESD Precaution

ATTENTION: Electrostatic Discharge (ESD) protection



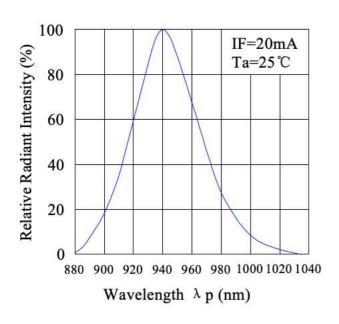
The symbol above denotes that ESD precaution is needed. ESD protection for GaP and AlGaAs based chips is necessary even though they are relatively safe in the presence of low static-electric discharge. Parts built with AlInGaP, GaN, or/and InGaN based chips are STATIC SENSITIVE devices. ESD precaution must be taken during design and assembly. If manual work or processing is needed, please ensure the device is adequately protected from ESD during the process.

Please be advised that normal static precautions should be taken in the handling and assembly of this device to prevent damage or degradation which may be induced by electrostatic discharge (ESD).

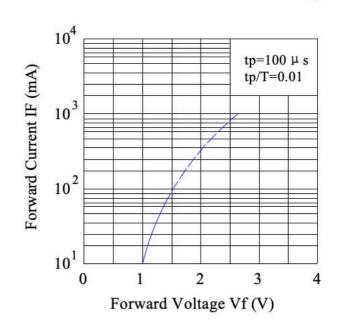


Typical Characteristic Curves Infrared

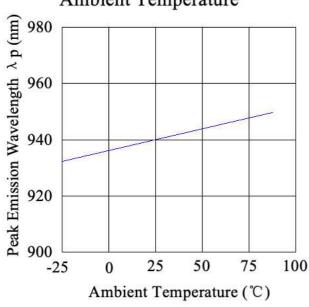
Spectral Distribution



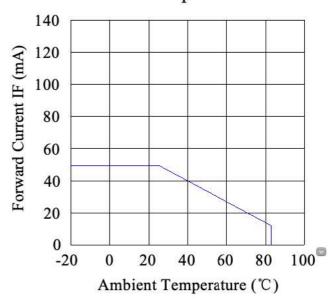
Forward Current & Forward Voltage



Peak Emission Wavelength & Ambient Temperature

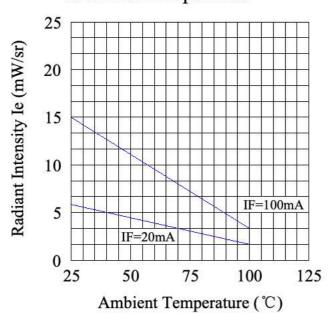


Forward Current & Ambient Temperature

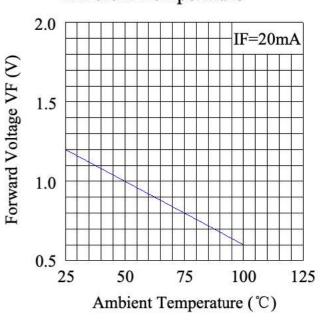




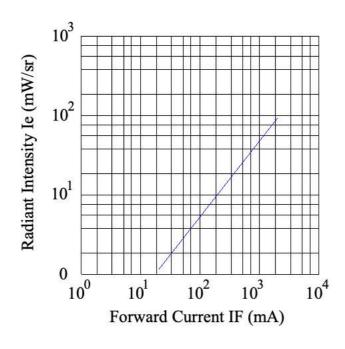
Relative Intensity & Ambient Temperature



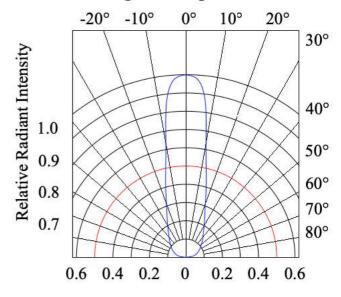
Forward Voltage & Ambient Temperature



Relative Intensity & Forward Current



Relative Radiant Intensity & Angular Displacement

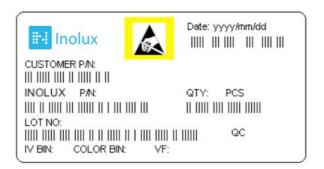




Ordering Information

Product	Emission Color	Test Current I _F (mA)	Ee (r	$F \in (MVV/Sr)$ $V \in (V)$			Orderable Part Number
INIA 040ALUIDOE	DE Infrared	20	IF=20mA	IF=100mA, tp=100µs, tp/T=0.01	IF=20mA	IF=100mA, tp=100μs, tp/T=0.01	INA 040ALUDOS
INA-912AHIR25	Infrared		6	15	1.2	1.6	INA-912AHIR25

Label Specifications





Inolux P/N:

I	N	Α	-	912	Α		HIR	25	Х	Х	Χ	Х
			Package		Lens	Color	View Angle	Customized Stamp-off				
	Inolux ad fra Axial	me		912A Lead fi Axi	rame	(Blank) = Clear Lens	HIR = 940nm	25 = 25 deg.				

Lot No.:

Z	2	0	1	7	01	24	001
Internal Tracker		Year (2017	, 2018,)		Month	Date	Serial



Reliability

Item	Frequency/ lots/ samples/ failures	Standards Reference	Conditions			
Precondition	For all reliability monitoring tests according to JEDEC Level 2	J-STD-020	1.) Baking at 85°C for 24hrs 2.) Moisture storage at 85°C/ 60% R.H. for 168hrs			
Solderability	1Q/ 1/ 22/ 0	JESD22-B102-B And CNS-5068	Accelerated aging 155°C/ 24hrs Tinning speed: 2.5+0.5cm/s Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s			
Resistance to soldering heat	CNS-5067 Dipping soldering to Soldering bath tem					
Operating life test	1Q/ 1/ 40/ 0	CNS-11829	1.) Precondition: 85°C baking for 24hrs 85°C/ 60%R.H. for 168hrs 2.) Tamb25°C; IF=20mA; duration 1000hrs			
High humidity, high temperature bias	1Q/ 1/ 45/ 0	JESD-A101-B	Tamb: 85°C Humidity: 85% R.H., IF=5mA Duration: 1000hrs			
High temperature bias	1Q/ 1/ 20	IN specs.	Tamb: 55°C IF=20mA Duration: 1000hrs			
Pulse life test	1Q/ 1/ 40/ 0		Tamb25°C, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125µs,T=1sec) Duration 500hrs)			
Temperature cycle	1Q/ 1/ 76/ 0	JESD-A104-A IEC 68-2-14, Nb	A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type			
High humidity storage test	1Q/ 1/ 40/ 0	CNS-6117	60+3°C 90+5/-10% R.H. for 500hrs			
High temperature storage test	1Q/ 1/ 40/ 0	CNS-554	100+10°C for 500hrs			
Low temperature storage test	1Q/ 1/ 40/ 0	CNS-6118	-40+5°C for 500hrs			



Revision History

Changes since last revision	Page	Version No.	Revision Date
Initial Release		1.0	01-27-2021

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- 2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.